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**SILICON NPN PHOTO TRANSISTOR**

**AT405-PT-02**

**DATA SHEET**

REV. : 1.0

DATE : 20-Apr.-2005

**FEATURE:**

- Fast Response Time.
- High Photo Sensitivity.
- Visible Light Cut-Off Type.
- Lead Free product, in compliance with RoHS.

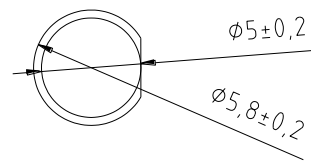
**DESCRIPTIONS:**

- AT405-PT-02 is a high speed and high sensitive silicon NPN phototransistor with exceptionally stable characteristics and high illumination sensitivity.
- Mounted in 5mm diameter black epoxy package.

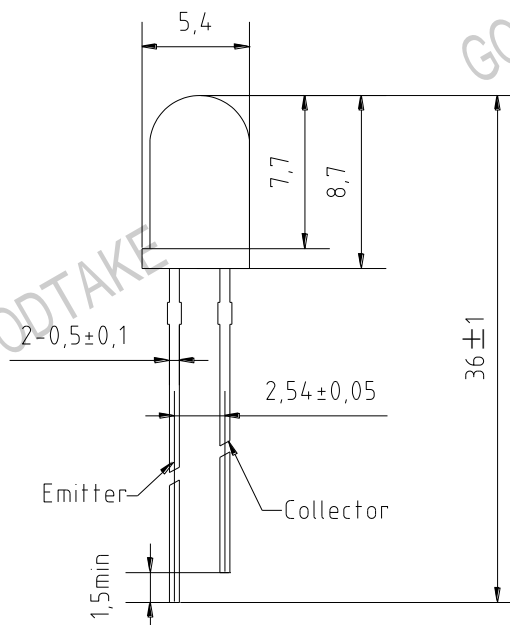
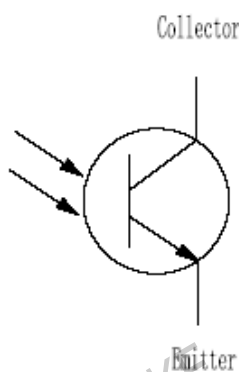
**APPLICATIONS:**

- Infrared Applied System.
- Floppy Disk Drive.
- Opto-Electronic Switch.

**DIMENSIONS:**



**INTERNAL CIRCUIT:**



**NOTE:** 1. All dimensions are in millimeter, tolerance is  $\pm 0.5$  unless otherwise noted.  
 2. Epoxy meniscus extends  $\leq 1$  mm down to the lead is allowed.

### ■ ABSOLUTE MAXIMUM RATINGS AT Ta=25°C

Parameter	Symbol	Ratings	Unit
Power Dissipation	P <sub>D</sub>	100	mW
Collector-Emitter Breakdown Voltage	V <sub>CEO</sub>	30	V
Emitter-Collector Breakdown Voltage	V <sub>ECO</sub>	5	V
Operating Temperature	T <sub>opr</sub>	-40~+85	°C
Storage Temperature	T <sub>stg</sub>	-55~+100	°C
Soldering Temperature	T <sub>sol</sub>	270°C for 6 sec Max (2mm from Body)	

### ■ TYPICAL ELECTRICAL & OPTICAL CHARACTERISTICS (Ta=25°C)

Parameter	Symbol	Min.	Type	Max.	Unit	Test Condition
Collector-Emitter Breakdown Voltage	V <sub>(BR)CEO</sub>	30			V	I <sub>C</sub> =100μA E <sub>e</sub> =0mW/cm <sup>2</sup>
Emitter-Collector Breakdown Voltage	V <sub>(BR)ECO</sub>	5			V	I <sub>E</sub> =100μA E <sub>e</sub> =0mW/cm <sup>2</sup>
Collector-Emitter Saturation Voltage	V <sub>CE(sat)</sub>			0.2	V	I <sub>C</sub> =2mA I <sub>B</sub> =100μA
Rise Time	T <sub>r</sub>		5		μS	V <sub>CE</sub> =5V I <sub>C</sub> =1mA R <sub>L</sub> =1000Ω
Fall Time	T <sub>f</sub>		5		μS	
Collector Dark Current	I <sub>CEO</sub>			100	nA	V <sub>CE</sub> =10V E <sub>e</sub> =0mW/cm <sup>2</sup>
On State Collector Current	I <sub>C(on)</sub>	8			mA	5V E <sub>e</sub> =1mW/cm <sup>2</sup> λ <sub>p</sub> =940nm
Peak Wavelength of Sensitive	λ <sub>p</sub>		940		nm	

**■ RELIABILITY TEST ITEMS AND CONDITIONS:**

<b>NO</b>	<b>Item</b>	<b>Test Conditions</b>	<b>Test Hours/Cycle</b>	<b>Sample Quantity</b>	<b>Test Result</b>
<b>1</b>	<b>Solder Heat</b>	<b>TEMP: 270°C ± 3°C</b>	<b>10 SEC</b>	<b>11 pcs</b>	<b>0 DEFECT</b>
<b>2</b>	<b>Temperature Cycle</b>	<b>H: +85°C 180min</b> $\updownarrow$ <b>10min</b> <b>L: -25°C 180min</b>	<b>16 cycles</b>	<b>22 pcs</b>	<b>0 DEFECT</b>
<b>3</b>	<b>Thermal Shock</b>	<b>H: +85°C 30min</b> $\updownarrow$ <b>30sec</b> <b>L: -25°C 30min</b>	<b>10 cycles</b>	<b>11 pcs</b>	<b>0 DEFECT</b>
<b>4</b>	<b>High Temperature Storage</b>	<b>TEMP: +25°C</b>	<b>1000 HRS</b>	<b>22 pcs</b>	<b>0 DEFECT</b>
<b>5</b>	<b>Low Temperature Storage</b>	<b>TEMP: -25°C</b>	<b>1000 HRS</b>	<b>22 pcs</b>	<b>0 DEFECT</b>
<b>6</b>	<b>High Temperature High Humidity Storage</b>	<b>85°C / 93% RH</b>	<b>1000HRS</b>	<b>22 pcs</b>	<b>0 DEFECT</b>

■ TYPICAL ELECTRO-OPTICAL CHARACTERISTICS CURVES:

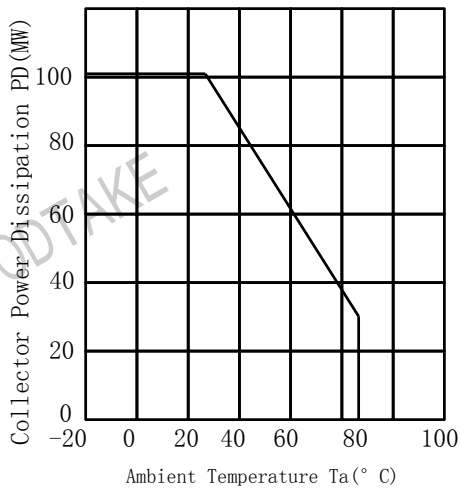


FIG. 1 Collector Pd vs Ta

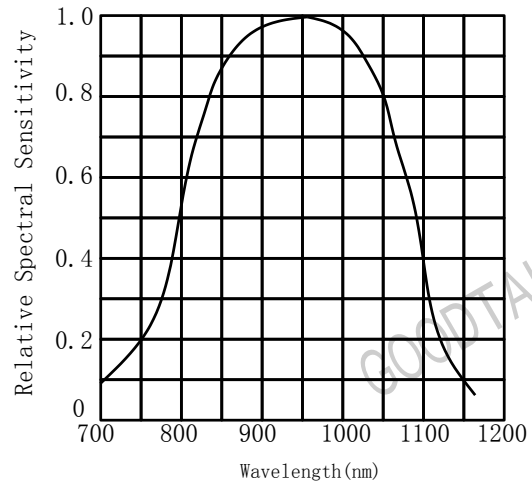


FIG. 2 Spectral Sensitivity

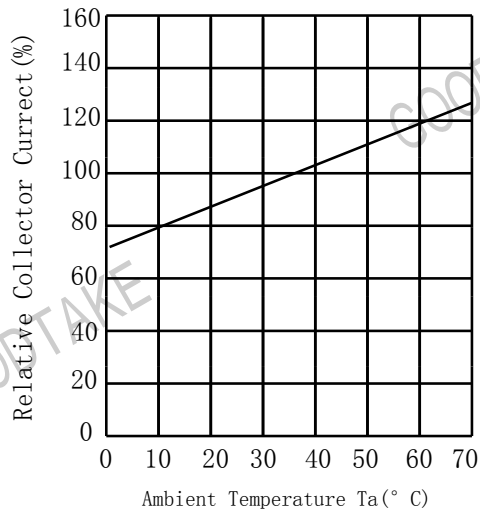


FIG. 3 Relative Ic vs. Ta

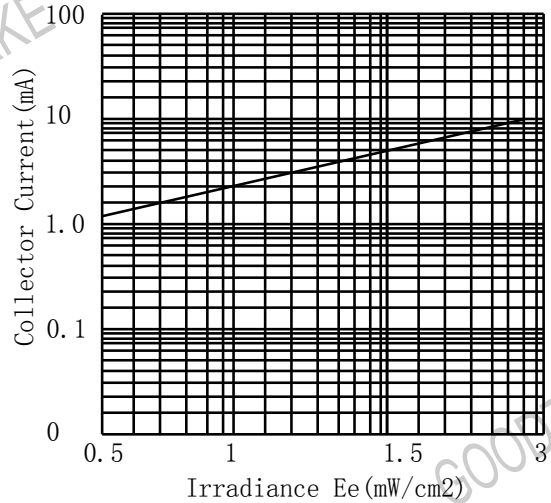


FIG. 4 Ic vs Iv

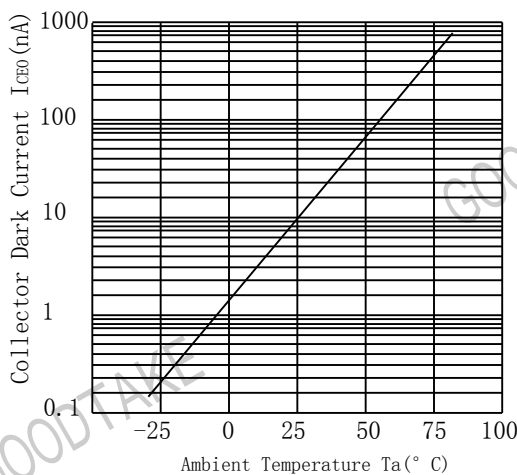


FIG. 5 Id vs Ta